AKB Meeting 2006
X-FAB Semiconductor Foundries AG Erfurt
27 October 2006

Agenda

10:00	J.Kosch	X-FAB Semiconductor Foundries
	Presentation X-FAB	
10:30	D.Celi	ST Microelectronics
	Hjei extraction issue	
11:00	J.Berkner	Infineon Technologies
	Negative slope in the HICUM Level0 transfer current - how to avoid?	
12:00	C.Thiele	Infineon Technologies
	Problems during the extraction of the HICUM-L0 model parameters IQFH and TFH	
12:30	Lunch	
13:30	J.Berkner	Infineon Technologies
	AKB member matters	
14:00	W.Kraus	Atmel
	PCM- and Physics-Based Statistical BJT Modeling	
14:30	B.Senepati	Austria Microsystems
	Parasitic PNP modeling in CMOS process	
15:00	T.Zimmer	Uni Bordeaux
	HBT's thermal impedance measurement	
15:30	F.Korndörfer	IHP
	Verfahren zur Bestimmung von CTH mit gepulsten Messungen	
16:00	R.Reuter	Freescale Semiconductor
	Nearly full automated extraction of VBIC models by optimization of special rf-goals	
16:30	F.Pourchon	ST Microelectronics
	BVCER simulation with HICUM model	